

1 *Supplementary Information*

2 **Desert locust-inspired wavelength-selective polarization**
3 **vision by all two-dimensional ferroelectric heterostructures**

4
5 Xiankai Lin,¹ Qian Zhang,^{2, *} Wenbo Li,¹ Fang Yi,³ Shihong Ma,¹ Guitian Qiu,¹
6 Jianxian Yi,^{1,2} Jiwei Chen,¹ Yingjie Luo,¹ Chunlei Zhang,¹ Guigang Zhou,^{1,2} Ziling
7 Chen,¹ and Qijie Liang^{1, *}

8
9 **AFFILIATIONS**

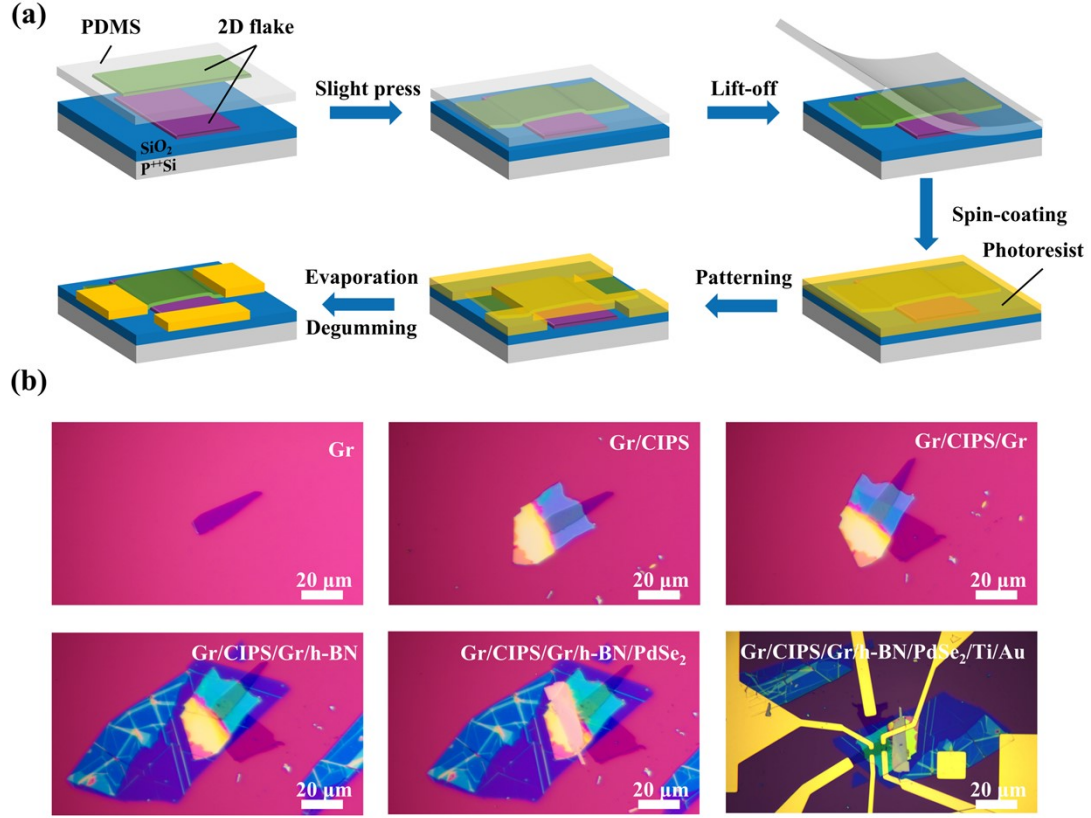
10 *¹Songshan Lake Materials Laboratory, Songshan Lake Mat Lab, Dongguan 523808,*
11 *China*

12 *²School of Materials, Shenzhen Campus of Sun Yat-sen University, No. 66, Gongchang*
13 *Road, Guangming District, Shenzhen 518107, China*

14 *³School of Materials Science and Engineering, Sun Yat-sen University, Guangzhou,*
15 *510275 P. R. China*

16 **E-mail: zhangqian6@mail.sysu.edu.cn; liangqijie@sslslab.org.cn*

17



1

2 **Figure S1. Fabrication process of the GCGhP ferroelectric heterostructure based**

3 **BPVS.** (a) Schematic of the fabrication process for the device structure. Using a PDMS-

4 assisted transfer technique, a 2D flake was first transferred onto a SiO₂/p⁺⁺Si substrate.

5 A second flake was then aligned and transferred onto the pre-positioned flake through

6 gentle pressing, followed by PDMS lift-off using a micromanipulator under an optical

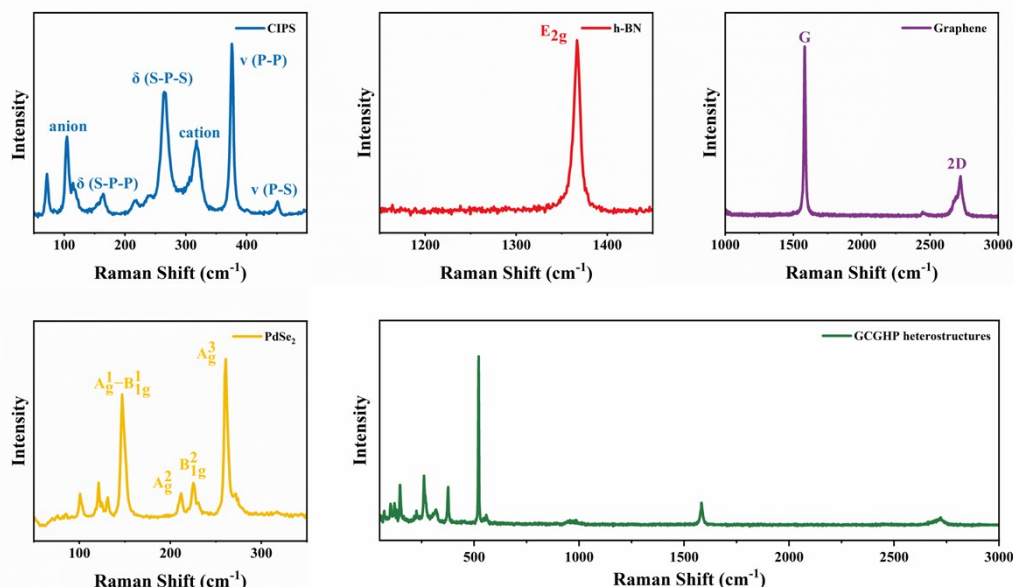
7 microscope, thereby forming the heterostructure. The process continued with spin-

8 coating of photoresist, UV photolithography patterning, metal evaporation, and

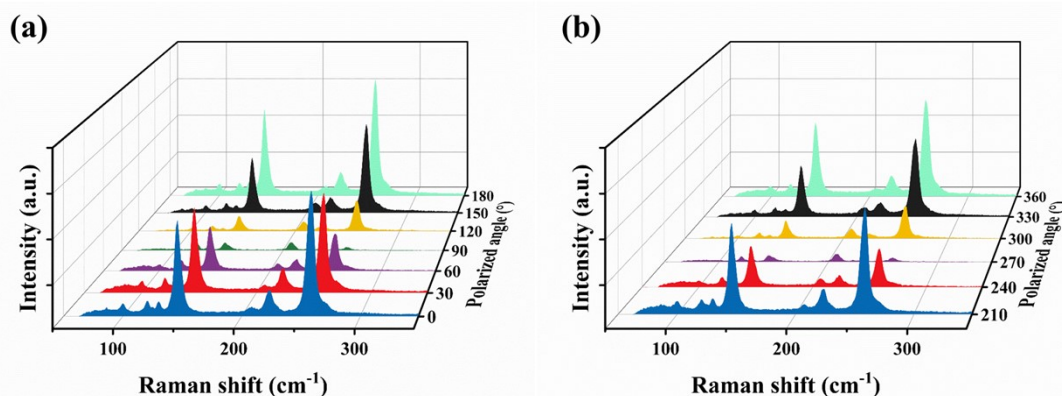
9 degumming, resulting in the final patterned device. (b) Optical microscope images of

10 BPVS at different process stages.

11

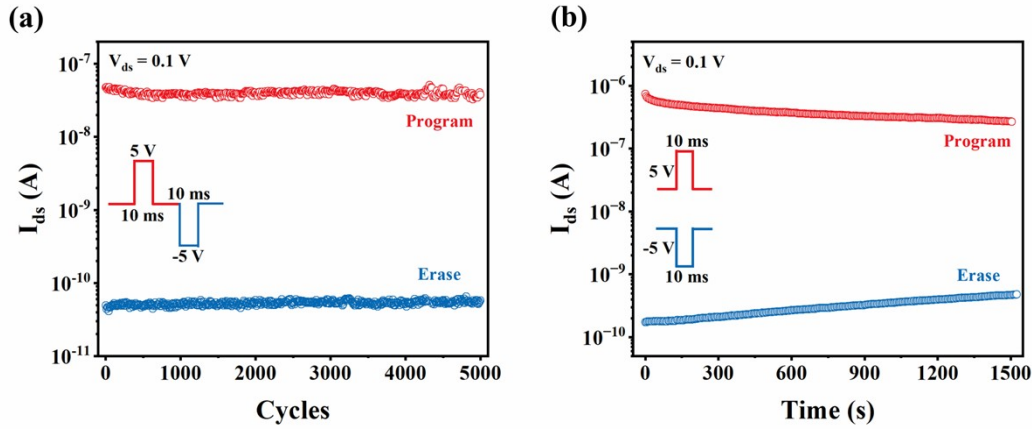


1
 2 **Figure S2. Raman spectra of PdSe₂, h-BN, Gr, CIPS, and GCGhP**
 3 **heterostructures.** For PdSe₂ nanosheets, four distinct peaks were shown at 147.0,
 4 211.9, 225.3, and 260.8 cm⁻¹. Correspond to the $A_g^1 - B_{1g}^1$, A_g^2 , B_{1g}^2 , A_g^3 mode. In
 5 addition, two distinct peaks appear at 100.8 and 121.1 cm⁻¹, indicating the low-layer
 6 nature of PdSe₂. For CIPS nanosheets, six vibrational peaks of activity modes were
 7 observed, including anion mode (104.4 cm⁻¹), δ (S-P-P) mode (164.0 cm⁻¹), δ (S-P-S)
 8 mode (264.4 cm⁻¹), cationic mode (317.4 cm⁻¹), ν (P-P) mode (375.6 cm⁻¹) and ν (P-S)
 9 mode (450.8) cm⁻¹). In contrast, the graphene nanosheets lacked D-peaks in their
 10 Raman spectra, which demonstrated their high-quality properties. In addition, the
 11 strength of the G-peak in the graphene sheet is much higher than that of the 2D peak,
 12 which indicates the multilayer nature of the graphene sheet. At the same time, h-BN
 13 exhibits Raman spectral characteristics similar to those previously reported¹.

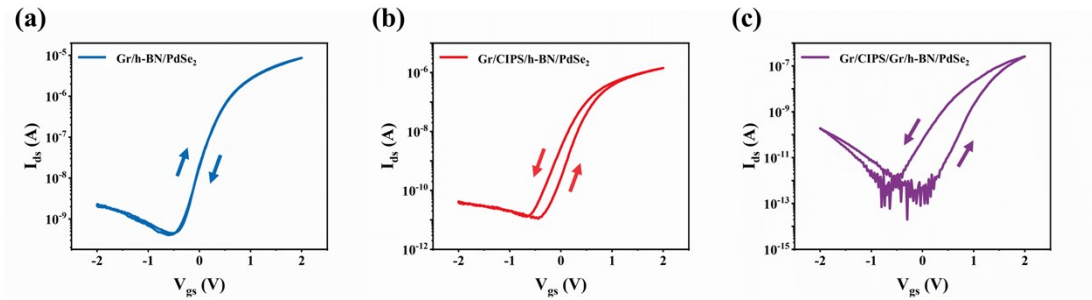


14

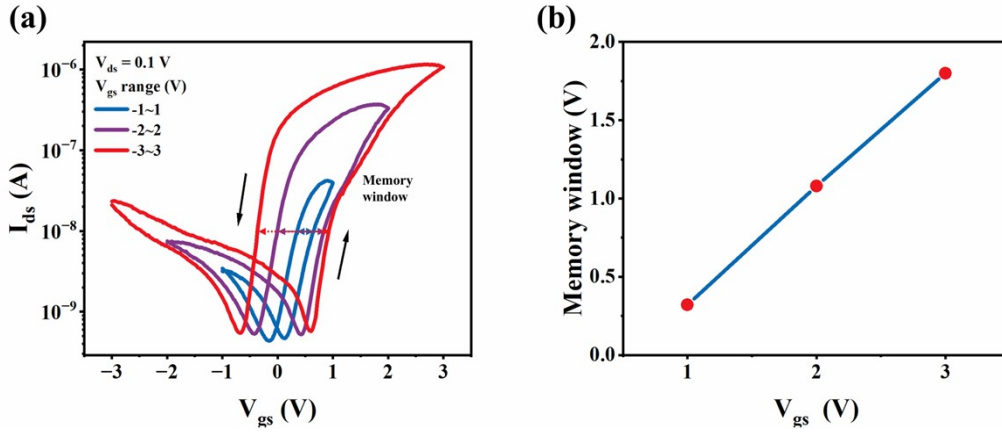
1 **Figure S3. The angle-resolved polarized Raman spectroscopy measurements of**
2 **the 2D PdSe₂ layer.**



3
4 **Figure S4. Non-volatile electronic memory behaviors of the BPVS. (a) Endurance**
5 **performance through more than 5,000 Program/Erase cycles. (b) Retention stability**
6 **through more than 1,500 s.**



7
8 **Figure S5. Transfer curves of PdSe₂-based transistors in different architectures.**
9 (a) The Gr/h-BN/PdSe₂ transistor has a hysteresis loop with a near-zero storage
10 window, indicating a clean interface between h-BN and PdSe₂ nanosheets and a tiny
11 charge-trapping effect at the interface. (b) The Gr/CIPS/h-BN/PdSe₂ transistor has a
12 significant hysteresis window, indicating that the memory behavior of the BPVS
13 originates from the ferroelectric medium, rather than the interface defect trapping of the
14 channel and the dielectric. (c) The Gr/CIPS/Gr/h-BN/PdSe₂ transistor has a larger
15 hysteresis window than the Gr/CIPS/h-BN/PdSe₂ transistor, due to compensation of
16 upward and downward polarization in CIPS by Gr.



1

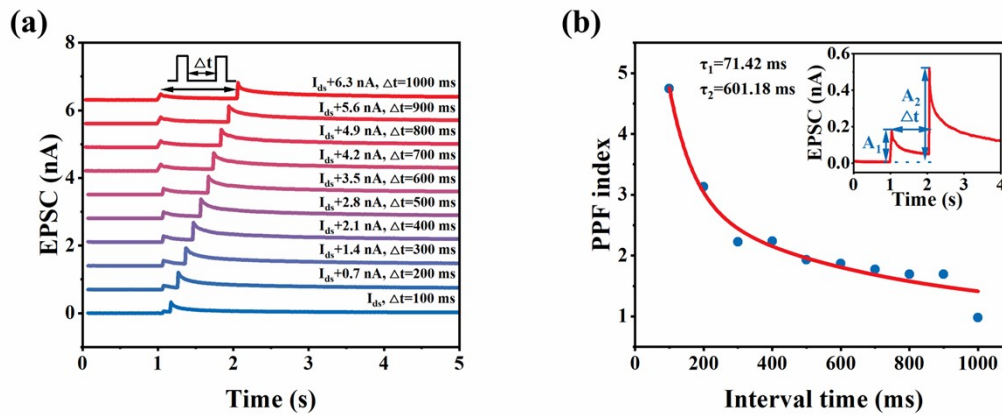
2 **Figure S6. Electrical characteristics of BPVS under different V_{gs} scanning**

3 **conditions.** (a) Transfer characteristics measured at $V_{ds} = 0.1$ V with an increasing gate

4 voltage sweep ranges (V_{gs} : ± 1 V to ± 3 V, step: 1 V). (b) The evolution of the memory

5 window under different V_{gs} scanning ranges is extracted from (a).

6



7

8 **Figure S7. PPF behavior characterization of the BPVS.** (a) Phenomenon of double

9 pulse peaks was triggered by two consecutive electrical pulses (amplitude: 4 V, width:

10 10 μ s) under different Δt . (b) PPF index values with respect to the interval of pulse

11 pairs, where the red line is the fitted curve using the double exponential decay function.

12

13 When two consecutive electrical pulses at different time intervals (Δt) are applied to
 14 the device and the reading voltage is set to 0.5 V, the EPSC amplitude caused by the
 15 second electrical pulse is significantly larger than that by the first one, which is similar
 16 to the PPF behavior in biological synapses. The PPF index is defined as

$$\text{PPF index} = \frac{(A_2 - A_1)}{A_1} \times 100\% \quad (1)$$

Where, A_1 and A_2 represent the first and second peaks of EPSC, respectively. It is worth noting that as Δt increases from 100 ms to 1000 ms, the PPF index decreases from 500% to 100%.

As Δt increased, the PPF index exhibits a declining trend, which can be fitted using a double-exponential function:²

$$\text{PPF index} = 1 + C_1 e^{\left(\frac{-\Delta t}{\tau_1}\right)} + C_2 e^{\left(\frac{-\Delta t}{\tau_2}\right)} \quad (2)$$

Where, C_1 and C_2 represent initial facilitation values respectively, and $\tau_1 = 71.42$ ms and $\tau_2 = 601.18$ ms represent fast decay time and slow decay time, respectively. The fitting results are comparable to those of biological synapses.³

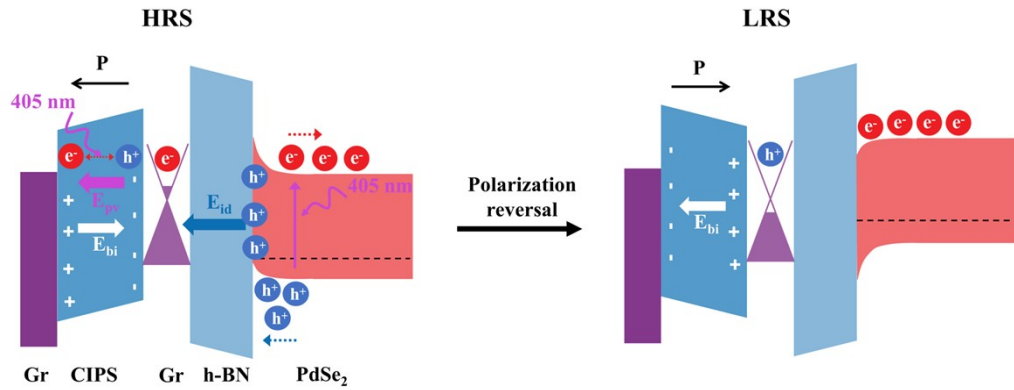
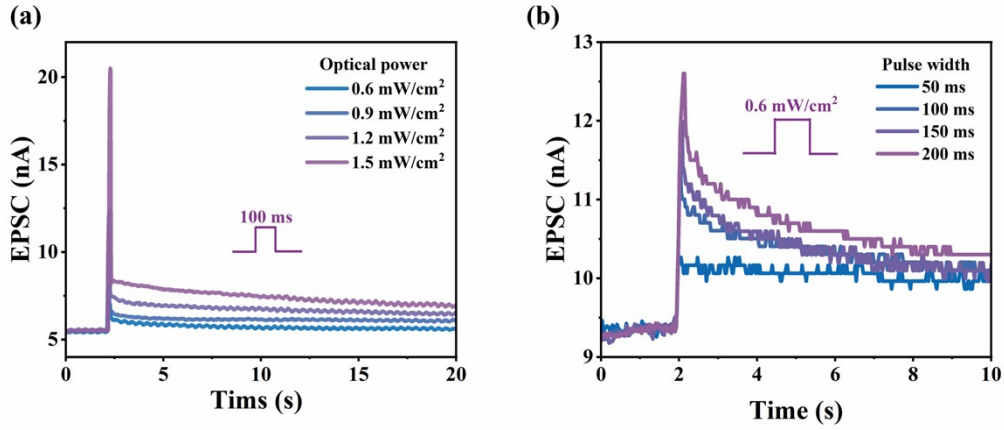


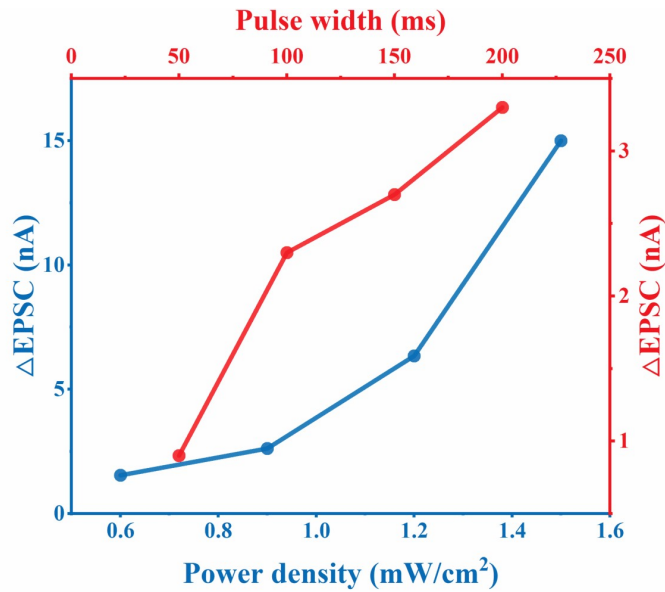
Figure S8. Schematic diagram of short-term memory characteristics induced by photovoltaic electric field (E_{pv}) and induced electric field (E_{id}) collaborate.

In the initial stage, a negative voltage pulse is applied to the gate, driving the transistor into a high resistance state (HRS). Subsequently, upon ultraviolet light irradiation, a large number of electron-hole pairs are generated within PdSe_2 . At this juncture, holes accumulate at the $\text{PdSe}_2/\text{h-BN}$ interface, inducing electron doping in graphene and generating an induced electric field within the heterostructure. Moreover, considering that CIPS is a non-centrosymmetric crystal, under ultraviolet light illumination, the momentum of photogenerated carriers exhibits an asymmetric distribution. This asymmetry leads to the generation of a E_{pv} within CIPS, which is opposite in direction

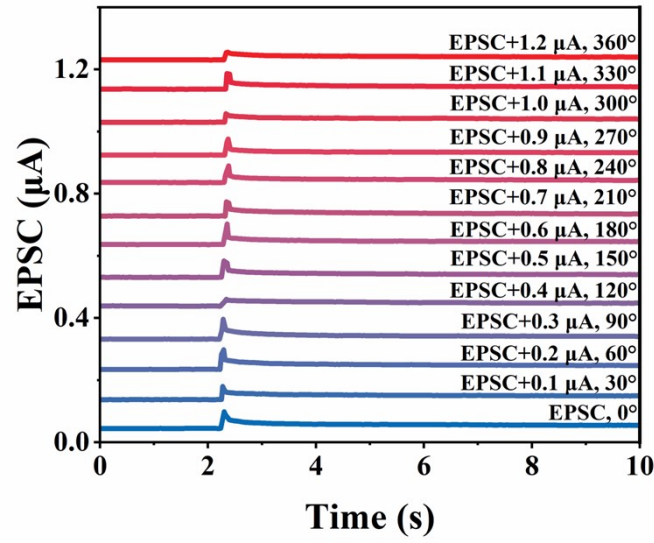
1 to the built-in electric field (E_{bi}).⁴ Ultimately, under the combined influence of E_{pv} and
 2 E_{id} , the polarization of CIPS is reversed. Consequently, the transistor transitions from
 3 a HRS to a low resistance state (LRS), and this LRS can be sustained for a short
 4 duration.



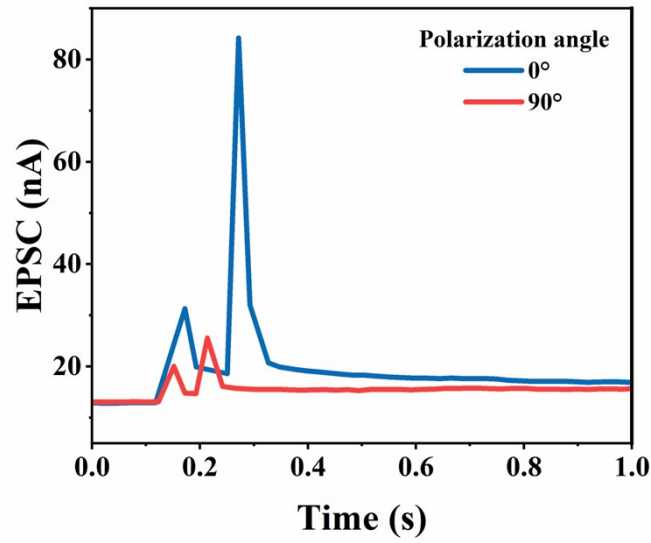
5
 6 **Figure S9. Characterization of optical synaptic plasticity.** Photocurrent responses
 7 triggered by single optical pulse with different (a) power densities and (b) pulse width,
 8 respectively.



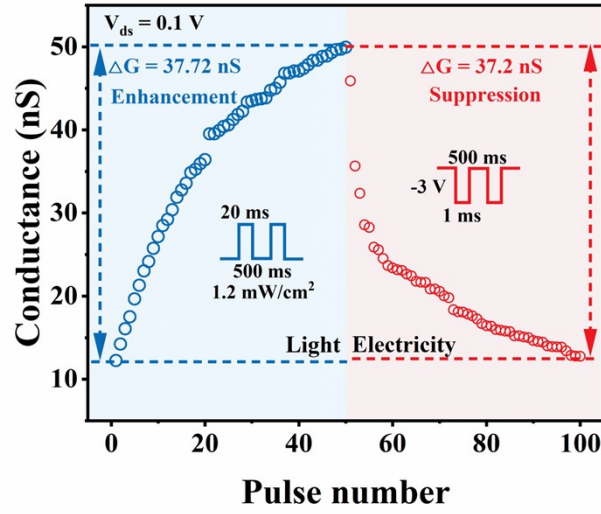
9
 10 **Figure S10. The modulation of EPSC by optical power and pulse width.**



1
2 **Figure S11. EPSC triggered by single optical pulse (intensity: 0.9 mW/cm² , width:**
3 **100 ms) with different polarization angles.**



4
5 **Figure S12. Phenomenon of double pulse peaks triggered by two consecutive**
6 **optical pulses (intensity: 0.9 mW/cm², width: 100 ms, interval: 100 ms) at 0° and**
7 **90° polarization angles, respectively.**

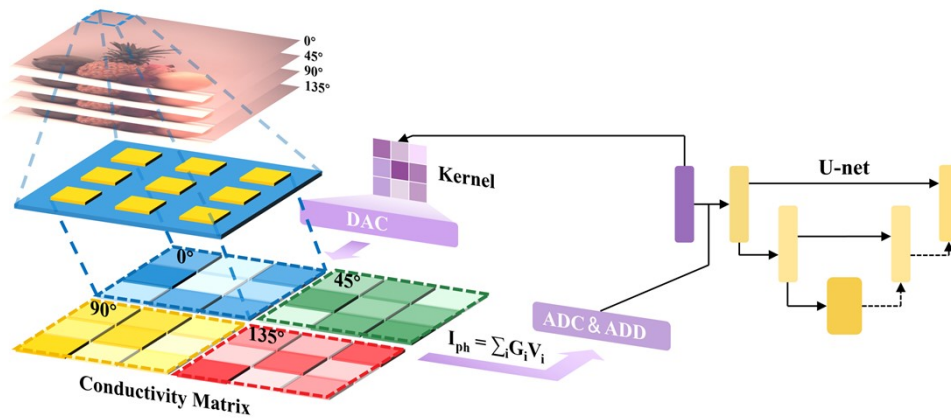


1
2 **Figure S13. The enhancement and suppression properties triggered by optical**
3 **pulses and electrical pulses.**

4 The average energy expenditure of a neuromorphic system during its training and
5 learning can be calculated using the following formula:

$$E_{ave} = \frac{(V_{ds}^2 \times \Delta G \times \Delta t)}{N}$$

6
7 Where V_{ds} is the training voltage, ΔG is the delta value of conductance before and after
8 training, Δt is the width of the training pulse and N is the number of pulses. The
9 calculated energy consumption of BPVS in enhancement (0.15 pJ per spike) and
10 suppression (7.44 fJ per spike).

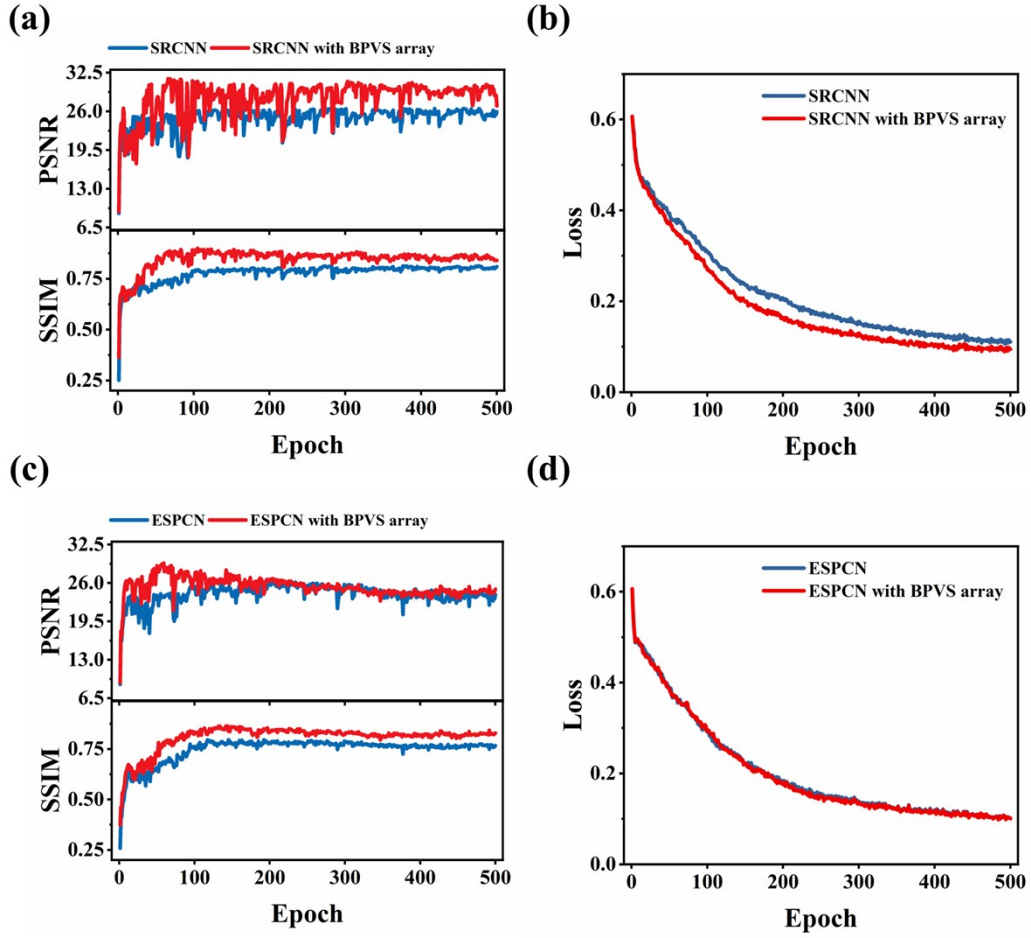


11
12 **Figure S14. Flow chart of polarization images convolution operation based on a**
13 **3×3 BPVS array.**

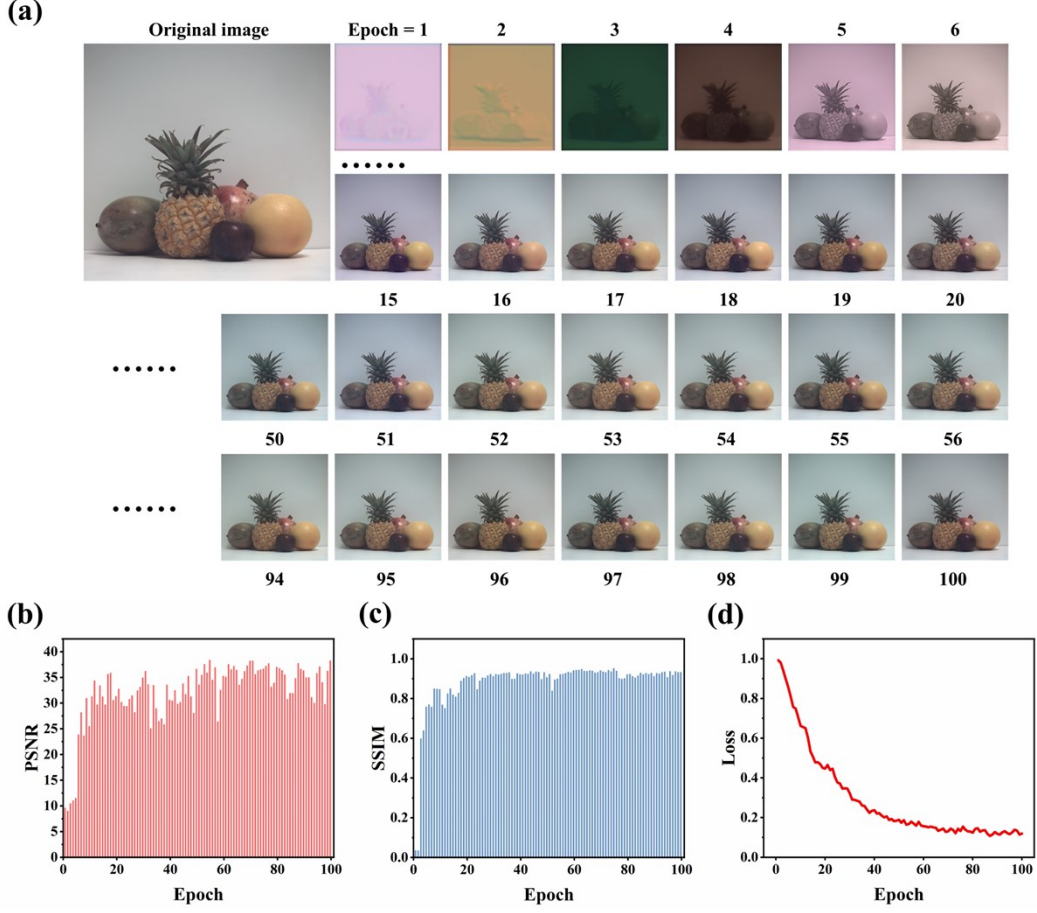
1 In the polarization image reconstruction, a 3×3 convolution kernel is utilized, which
 2 corresponds to the first convolution layer of the U-net model. The convolution kernel
 3 accomplishes image local - feature extraction via a 2D discrete convolution operation,
 4 and its functional matrix can be expressed as:

$$\begin{aligned} 5 \quad W &= [[w_{11}, w_{12}, w_{13}], \\ 6 \quad & [w_{21}, w_{22}, w_{23}], \\ 7 \quad & [w_{31}, w_{32}, w_{33}]] \end{aligned}$$

8 where w_{ij} represents trainable weight parameters, which are optimized by gradient
 9 descent algorithm. At the hardware implementation level, the normalized weight
 10 parameters are transformed into an analog voltage signal V_{ds} by a high-precision digital
 11 -to-analog converter (DAC) and then loaded onto a 3×3 BPVS array. The conductivity
 12 state of each BPVS unit corresponds to the pixel value of the input image. Images with
 13 different polarization angles are successively mapped from “pixel value- conductance
 14 value” to achieve 36-level (6-bit) discrete conductivity state quantization. Next, the
 15 BPVS array accomplishes the convolution operation through the channel current
 16 modulation of the van der Waals heterojunction. When V_{ds} is applied to the 3×3 BPVS
 17 array, the current output of each BPVS unit is $I_{ph} = G_i \cdot V_i$ (where G_i is the device
 18 conductance). The convolution result is obtained after summation by an integrating
 19 circuit, obviating the pixel-by-pixel multiplication-summation (MAC) operation of a
 20 traditional digital circuit.⁵



1
2 **Figure S15. Comparative evaluation of SR reconstruction performance.** (a, b)
3 PSNR, SSIM, and loss values for polarization images reconstructed by the SRCNN
4 model with and without the BPVS array, respectively. (c, d) PSNR, SSIM, and loss
5 values for the ESPCN model with and without the BPVS array, respectively.



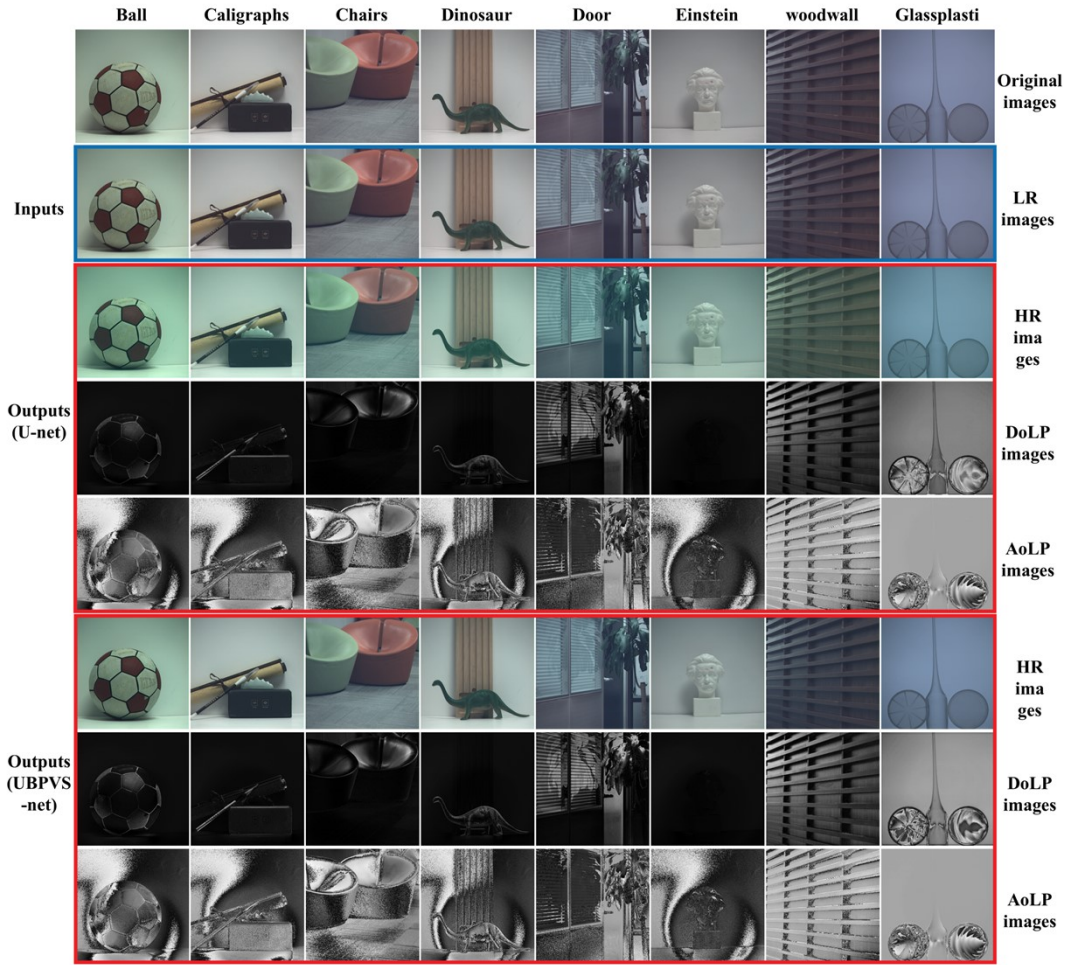
1

2 **Figure S16. Demonstration of SR reconstruction of color polarization images with**
3 **increasing iterations based on UBPVS-net architecture.** (a) Visual results from the
4 first to the 100th training cycle. (b-d) PSNR, SSIM and loss values were calculated
5 based on reconstructed polarization images from the first to the 100th training cycle.

6 The both PSNR and SSIM plateau after approximately 20 epochs, indicating that the
7 model had effectively completed learning the global image features such as structure,
8 luminance, and contrast. Beyond this stage, the model continued to refine subtle pixel-
9 level deviations, with the loss continuing to decline gradually until full convergence. It
10 should be noted that PSNR is derived from a logarithmic transformation of the mean

11 square error (MSE) ($PSNR = 10 \log_{10} \left(\frac{n^2}{MSE} \right)$, n is defined as the total pixel count). As
12 a result, even minor variations in MSE can lead to noticeable fluctuations in PSNR
13 values, which explains the pronounced PSNR fluctuations observed during the training
14 stages.

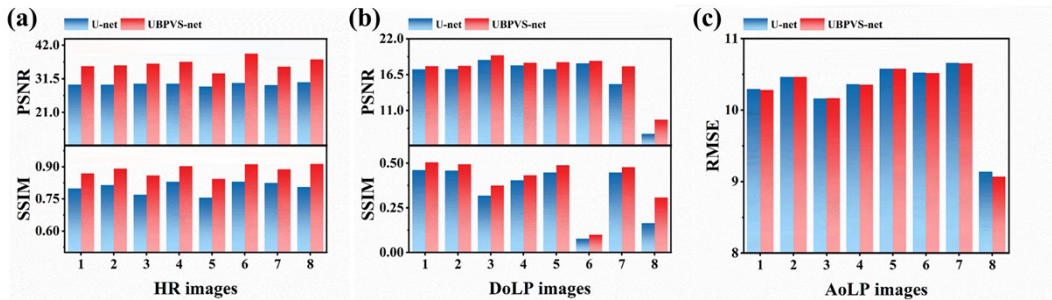
1



2

3 **Figure S17. Demonstration of SR reconstruction of multiple color polarization**
 4 **images based on UBPVS-net and U-net architectures.**

5



6 **Figure S18. Evaluation indices of reconstructed multiple color polarization images**
 7 **UBPVS-net and U-net architectures. (a, b) PSNR and SSIM values were calculated**
 8 **from the reconstructed HR images and DoLP images. (c) The RMSE values were**
 9 **calculated from the reconstructed AoLP images. The numbers 1, 2, 3, 4, 5, 6, 7, and 8**

1 represent the ball, calligraphset, chairs, dinosaur, door, Einstein, woodwall, and
2 glassplastic, respectively.

3 **Table S1. Comparison of the structure and performance of other types of 2D**
4 **ferroelectric devices.**

Configuration	Structure	Cycle Endurability	Electronic Retention	Electronic LTP/LTD Endurability	Ref.
Two-terminal	Gr/ α -In ₂ Se ₃ /Gr	-	-	3 cycles, 400 pulse numbers	6
Two-terminal	Ti/ α -In ₂ Se ₃ /Au	>100	>5000 s	-	7
Three-terminal	Si/SiO ₂ /SnSe/Ti/Au	~50	>3600 s	4 cycles, 250 pulse numbers	8
Three-terminal	IGZO/SnO/SnS	-	-	8 cycles, 650 pulse numbers	9
Two-terminal	Au/CIPS/Gr	-	-	10 cycles, 400 pulse numbers	10
Two-terminal	Au/CIPS/MoS ₂ /Gr	-	-	-	11
Three-terminal	Au/CIPS/h-BN/ReS ₂	-	>1000 s	-	4
Three-terminal	Au/CIPS/MoS ₂	-	-	-	12
Four-terminal	Au/CIPS/h-BN/WSe ₂	-	-	-	13
Two-terminal	Au/CIPS/Ti	>100	>2000 s	-	14
Three-terminal	Gr/CIPS/Gr/h-BN/PdSe ₂	>5000	>1500 s	90 cycles, 9000 pulse numbers	This work

5

6 **Table S2. Comparison of the structure and performance of other types of bionic**
7 **polarization visual devices.**

Structure	Mechanism	Polarization type	On/Off	Wavelength	Synaptic plasticity	Network	Ref.
H-PVKs/SWNTs	Defects capture	Circular	-	395 nm to 470 nm	EPSC, PPF, STP, LTP and SEDP	SNN (MNIST)	15
Cl ₂ -NDI/PBI-1	Defects capture	Linear	>10 ⁴	414 nm, 645 nm	EPSC, IPSC and STDP	-	16
3D Gr/MoS ₂	Defects capture	Linear	~10 ³	365 nm to 808 nm	IPSC, PPF, STD, and LTD	-	17
ReS ₂	Defects capture	Linear	>10 ³	552 nm, 860 nm	EPSC, STDP and SEDP	-	18
UiO-66-NH ₂ /ReS ₂	Defects capture	Linear	>10 ³	552 nm, 860 nm	EPSC	-	19
PbS QDs/Gr	Defects capture	Linear	-	405 nm	EPSC, IPSC, LTP, and LTD	ANNs (MNIST)	20
C8-BTBT	Defects capture	Linear	-	365 nm, 525 nm	-	-	21
ReS ₂ /GeSe ₂	Defects capture	Linear	~10 ²	405 nm, 808 nm	EPSC, IPSC, LTP, and LTD	ANNs	22
Gr/CIPS/Gr/h-BN/PdSe ₂	Ferroelectric polarization	Linear	>10 ³	405 nm	EPSC, PPF, STP, LTP, LTD, and SEDP	UBPVS-net (Polarization images SR reconstruction)	This work

1

2 References

- 3 1 J. Zha, S. Shi, A. Chaturvedi, H. Huang, P. Yang, Y. Yao, S. Li, Y. Xia, Z. Zhang,
- 4 W. Wang, H. Wang, S. Wang, Z. Yuan, Z. Yang, Q. He, H. Tai, E. H. T. Teo, H.
- 5 Yu, J. C. Ho, Z. Wang, H. Zhang and C. Tan, *Adv. Mater.*, 2023, **35**, 2211598.
- 6 2 S. M. Kwon, S. W. Cho, M. Kim, J. S. Heo, Y. Kim and S. K. Park, *Adv. Mater.*,

- 1 2019, **31**, 1906433.
- 2 3 R. S. Zucker and W. G. Regehr, *Annu. Rev. Physiol.*, 2002, **64**, 355–405.
- 3 4 M. Soliman, K. Maity, A. Gloppe, A. Mahmoudi, A. Ouerghi, B. Doudin, B.
- 4 Kundys and J.-F. Dayen, *ACS Appl. Mater. Interfaces*, 2023, **15**, 15732–15744.
- 5 5 Y. Xia, N. Lin, J. Zha, H. Huang, Y. Zhang, H. Liu, J. Tong, S. Xu, P. Yang, H.
- 6 Wang, L. Zheng, Z. Zhang, Z. Yang, Y. Chen, H. P. Chan, Z. Wang and C. Tan,
- 7 *Adv. Mater.*, 2024, **36**, 2403785.
- 8 6 J. Zeng, G. Feng, G. Wu, J. Liu, Q. Zhao, H. Wang, S. Wu, X. Wang, Y. Chen, S.
- 9 Han, B. Tian, C. Duan, T. Lin, J. Ge, H. Shen, X. Meng, J. Chu and J. Wang, *Adv.*
- 10 *Funct. Mater.*, 2024, **34**, 2313010.
- 11 7 Y. Zhang, L. Wang, H. Chen, T. Ma, X. Lu and K. P. Loh, *Adv. Elect. Mater.*, 2021,
- 12 **7**, 2100609.
- 13 8 Z. Liu, Y. Wang, Y. Zhang, S. Sun, T. Zhang, Y. Zeng, L. Hu, F. Zhuge, B. Lu, X.
- 14 Pan and Z. Ye, *Adv. Mater.*, 2025, **37**, 2410783.
- 15 9 R. Yang, D. Hu, Q. Chen, Z. Wang, B. Lu, Z. Ye, X. Li and J. Lu, *Adv. Funct.*
- 16 *Mater.*, 2025, **35**, 2414210.
- 17 10 Y. Liu, Y. Wu, H. Han, Y. Wang, R. Peng, K. Liu, D. Yi, C. Nan and J. Ma, *Adv.*
- 18 *Funct. Mater.*, 2024, **34**, 2306945.
- 19 11 Z. Wang, J. Li, X. Fan, W. Tang, H. Zhu and L. Li, *Adv. Mater. Tech.*, 2024,
- 20 2401589.
- 21 12 X. Wang, P. Yu, Z. Lei, C. Zhu, X. Cao, F. Liu, L. You, Q. Zeng, Y. Deng, C. Zhu,
- 22 J. Zhou, Q. Fu, J. Wang, Y. Huang and Z. Liu, *Nat. Commun.*, 2019, **10**, 3037.
- 23 13 A. Ram, K. Maity, C. Marchand, A. Mahmoudi, A. R. Kshirsagar, M. Soliman, T.
- 24 Taniguchi, K. Watanabe, B. Doudin, A. Ouerghi, S. Reichardt, I. O'Connor and J.-
- 25 F. Dayen, *ACS Nano*, 2023, **17**, 21865–21877.
- 26 14 B. Li, S. Li, H. Wang, L. Chen, L. Liu, X. Feng, Y. Li, J. Chen, X. Gong and K.
- 27 Ang, *Adv. Elect. Mater.*, 2020, **6**, 2000760.
- 28 15 Q. Liu, Q. Wei, H. Ren, L. Zhou, Y. Zhou, P. Wang, C. Wang, J. Yin and M. Li,
- 29 *Nat. Commun.*, 2023, **14**, 7179.
- 30 16 J. H. Kim, M. Stolte and F. Würthner, *ACS Nano*, 2022, **16**, 19523–19532.

- 1 17 Y. Li, Y. Zhang, Y. Wang, J. Sun, Q. You, M. Zhu, L. Li and T. Deng, *Adv. Funct.*
2 *Mater.*, 2024, **34**, 2302288.
- 3 18 D. Xie, K. Yin, Z.-J. Yang, H. Huang, X. Li, Z. Shu, H. Duan, J. He and J. Jiang,
4 *Mater. Horiz.*, 2022, **9**, 1448–1459.
- 5 19 D. Xie, G. Gao, B. Tian, Z. Shu, H. Duan, W. Zhao, J. He and J. Jiang, *Adv. Mater.*,
6 2023, **35**, 2212118.
- 7 20 K.-J. Lee, J. H. Kim, S. Jeon, C. W. Shin, H.-R. Kim, H.-G. Park and J. Kim, *Nano*
8 *Lett.*, 2024, **24**, 2421–2427.
- 9 21 J. Pan, Y. Wu, X. Zhang, J. Chen, J. Wang, S. Cheng, X. Wu, X. Zhang and J. Jie,
10 *Nat. Commun.*, 2022, **13**, 6629.
- 11 22 T. Guo, S. Li, Y. N. Zhou, W. D. Lu, Y. Yan and Y. A. Wu, *Nat. Commun.*, 2024,
12 **15**, 6731.
- 13